

Form PTO-1449 (Modified) INFORMATION DISCLOSURE CITATION IN AN APPLICATION	Application No.	TBD 10/728036
	Filing Date	December 3, 2003
	First Named Inventor	LU, Cam L.
	Group Art Unit	TBD 2825
	Examiner Name	TBD Siek, V.
Sheet 1 of 1		Attorney Docket No. 03-1978 81641

U.S. PATENT DOCUMENTS									
EXAMINER INITIALS*	CITE NO.	COPY NOT ENCLOSED PER 37 CFR § 1.98(d)	U.S. PATENT DOCUMENT		NAME OF INVENTOR OR APPLICANT	DATE OF ISSUANCE OR PUBLICATIO N (MM-DD- YYYY)	CLASS	SUB CLASS	FILING DATE (if appropriate)
			PATENT, PUB., OR APP. NO.	KIND CODE (if known)					

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
EXAMINE R INITIALS*	CITE NO.	COPY NOT ENCLOSED PER 37 CFR § 1.98(d)	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
VS	AA	—	BENWARE, B.R.; Effectiveness Comparisons of Outlier Screening Methods for Frequency Dependent Defects on Complex ASICs; LSI Logic Corporation and IC Design & Test Lab, Portland State University. Apr 27 - May 1 - 2003, 11-8.

Examiner Signature	VUTHE SIEK	Date Considered	8/13/05
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.			